AMENDMENTS TO THE CLAIMS:

The listing of claims shown below will replace all prior versions, and listings, of claims in the Application:

Sub-7

(Amended)

A MEMSMicro-Electro-Mechanical System apparatus, comprising:

a substrate;

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a passivation layer on the substrate, the passivation layer having a top surface; and a microstructure suspended above the substrate, the microstructure having a bottom

surface facing the top surface of the passivation layer;

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wherein the passivation layer is patterned is patterned to form a plurality of spaced

protuberances so that the top surface of the passivation layer is substantially different from

the bottom surface of the microstructure.

2. (Cancelled)

3. (Amended) The MEMS Micro-Electro-Mechanical System apparatus of claim 21,

wherein the bottom surface of the microstructure is substantially flat.

fig. 3A

4. (Amended) The MEMS-Midro-Electro-Mechanical System apparatus of claim 21,

wherein at least one of the protuberances has a square cross section.

fig.3B

5. (Amended) The MEMS-Micro-Dectro-Mechanical System apparatus of claim 21,

(prev 269/132)

Swherein at least one of the protuberances has a rectangular cross section.

fig.3C

- 6. (Amended) The MEMS-Micro-Electro-Mechanical System apparatus of claim 21, wherein at least one of the protuberances has a hexagonal cross section.
- 7. (Amended) The MEMS-Micro-Electro-Mechanical System apparatus of claim 1, wherein the passivation layer is patterned to form a mesh.

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8. (Amended) The MEMS-Micro-Electro-Mechanical System apparatus of claim 7, wherein the bottom surface of the microstructure is substantially flat.

fig.3E

9. (Amended) The MEMS-Micro-Electro-Mechanical System apparatus of claim 7, wherein the mesh is a square mesh.

fig. 30

- 10. (Amended) The MEMS-Micro-Electro-Mechanical System apparatus of claim 7, wherein the mesh is a hexagonal mesh.
- 11. (Amended) The MEMS-Micro-Electro-Mechanical System apparatus of claim 1, wherein the passivation layer comprises polyimide.
- 12. (Amended) The MEMS-Micro-Electro-Mechanical System apparatus of claim 1, wherein the passivation layer comprises silicon nitride.

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(Amended)

A MEMS Micro-Electro-Mechanical System apparatus, comprising:

a substrate

a passivation layer on the substrate, the passivation layer having a top surface;

figs.1,2

a support attached to the substrate; and

a beam attached at one end to the support and suspended above the substrate, the beam having a bottom surface facing the top surface of the passivation layer;

wherein the passivation layer is patterned to form a plurality of spaced protuberances so that the top surface of the passivation layer is substantially different from the bottom surface of the beam.

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14. (Amended) The MEMS Micro-Electro-Mechanical System apparatus of claim 13, further comprising a second support attached to the substrate and wherein the beam is attached to the second support at a second end.

fig. 2

- 15. (Amended) The MEMS Micro-Electro-Mechanical System apparatus of claim 13, further comprising a bottom electrode on the substrate and underneath the bottom surface of the beam.
- 16. (Cancelled)
- 17. (Amended) The MEMS-Micro-Electro-Mechanical System apparatus of claim 1613,

(prev 269/132)

Such

wherein the bottom surface of the microstructure beam is substantially flat.

fig. 3A

18. (Amended) The MEMS-Micro-Electro-Mechanical System apparatus of claim 1613, wherein at least one of the protuberances has a square cross section.

fig. 3B

19. (Amended) The MEMS-Micro-Electro-Mechanical System apparatus of claim 1613, wherein at least one of the protuberances has a rectangular cross section.

fig.3C

20. (Amended) The MEMS Micro-Electro-Mechanical System apparatus of claim 1613, wherein at least one of the protuberances has a hexagonal cross section.

- 21. (Amended) The MEMS-Micro-Electro-Mechanical System apparatus of claim 13, wherein the passivation layer is patterned to form a mesh.
- 22. (Amended) The MEMS Micro-Electro-Mechanical System apparatus of claim 21, wherein the bottom surface of the microstructure beam is substantially flat.

fig.35

23. (Amended) The <u>MEMS_Micro-Electro-Mechanical System_apparatus of claim 21, wherein the mesh is a square mesh.</u>

fig ,30

24. (Amended) The MEMS-Micro-Electro-Mechanical System apparatus of claim 21, wherein the mesh is a hexagonal mesh.

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25. (Amended) The MEMS-Micro-Electro-Mechanical System apparatus of claim 13, wherein the passivation layer comprises polyimide.

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26. (Amended) The MEMS Micro-Electro-Mechanical System apparatus of claim 13, wherein the passivation layer comprises silicon nitride.

Claims 27-38 (Previously Cancelled)

P.5 **R5** 39. (New) The Micro-Electro-Mechanical System apparatus of claim 1, wherein the passivation layer is made of a dielectric material selected from the group consisting of silicon oxide, strontium titanate oxide, barium strontium titanate, and benzocyclobutene.

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40. (New) The Micro-Electro-Mechanical System apparatus of claim 13, wherein the passivation layer is made of a dielectric material selected from the group consisting of silicon oxide, strontium titanate oxide, barium strontium titanate, and benzocyclobutene.